Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,884	SHIRAISHI ET AL.
Examiner	Art Unit
Paul D. Kim	3729

SEARCHED			
Class	Subclass	Date	Examiner
29	25.35 603.04 603.06 603.07	8/19/2005	PK
156	64 307.1 37 <b>9</b>		
360	294.4 294.6	V	
· · ·			-
			-

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	/			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Reviewed Parent Application 09/933,774 (US PAT. 6,690,551)	8/19/2005	PK	
Text Search EAST/NPL (IEEE)	8/19/2005	РК	
		- , - , -	